Docket No.

242006US2

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Toshifumi IWASAKI

SERIAL NO: NEW APPLICATION

GAU:

FILED:

HEREWITH

EXAMINER:

FOR:

METHOD OF DESIGNING SEMICONDUCTOR DEVICE ALLOWING CONTROL OF CURRENT DRIVING

CAPABILITY DEPENDING ON SHAPE OF ELEMENT FORMING REGION

# INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR .

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

#### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check is attached in the amount required under 37 CFR §1.17(p).

### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

## **DEPOSIT ACCOUNT**

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment form is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

Registration No. 24,913

C. Irvin McClelland Registration Manage 21,124

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| Form PTO 1449<br>(Modified)  | U.S. DEPARTMENT OF COMMERCE<br>PATENT AND TRADEMARK OFFICE |   |               | ATTY DOCKET NO.              |                 | SERIAL NO.                              |                               |             |  |
|--|--|---|---------------|------------------------------|-----------------|---|-------------------------------|-------------|--|
| (Modified)   |  | FAIENI AND INAL   | DEWARK OFFICE | 242006US2                    | NEW APPLICATION |   |                               |             |  |
|  | DEEE   |   |               | APPLICANT                    |                 |   |                               |             |  |
| LISTOF   | KEFE   | RENCES CITED BY AP  | PLICANI       | Toshifumi IWASAKI            |                 |   |                               |             |  |
|  |  |   |               | FILING DATE                  |                 | GROUP                                   |                               |             |  |
|  |  |   |               | HEREWITH                     | <u> </u>        |   |                               |             |  |
| U.S. PATENT DOCUMENTS  |  |   |               |                              |                 |   |                               |             |  |
| EXAMINER<br>INITIAL  |  | DOCUMENT<br>NUMBER  | DATE          | NAME                         | CLASS           | SUB<br>CLASS                            | FILING DATE<br>IF APPROPRIATE |             |  |
|  | AA   |   |               |                              |                 |   |                               |             |  |
|  | AB   |   |               |                              |                 |   |                               |             |  |
|  | AC   |   |               |                              |                 |   |                               |             |  |
|  | AD   |   |               |                              |                 |   |                               |             |  |
|  | AE   |   |               |                              |                 |   |                               |             |  |
|  | AF   |   |               |                              |                 |   |                               |             |  |
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|  | AM   |   |               |                              |                 |   |                               |             |  |
|  | AN   | i   |               |                              | 1               |   |                               |             |  |
| FOREIGN PATENT DOCUMENTS   |  |   |               |                              |                 |   |                               |             |  |
|  |  | DOCUMENT<br>NUMBER  | DATE          | COUNTRY                      |                 | YE                                      | TRANSLATION<br>YES            |             |  |
|  | AO   | 11-186495   | 07/09/99      | Japan (with English extract) |                 |   |                               | ×           |  |
|  | AP   |   |               |                              |                 |   |                               |             |  |
|  | AQ   |   |               |                              |                 |   |                               |             |  |
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|  | AT   |   |               |                              |                 |   |                               |             |  |
|  | AU   |   |               |                              |                 |   |                               |             |  |
|  | ΑV   |   |               |                              |                 |   |                               |             |  |
| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)  |  |   |               |                              |                 |   |                               |             |  |
|  | AW   | Gregory SCOTT, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress", IEDM, IEEE, 1999, pgs. 827-830 |               |                              |                 |   |                               |             |  |
|  | AX   |   |               |                              |                 |   |                               | <del></del> |  |
|  | AY   |   |               |                              |                 |   |                               |             |  |
|  | AZ   |   |               |                              | Add             | Additional References sheet(s) attached |                               |             |  |
| Examiner   |  |   |               |                              | Date Co         | Date Considered                         |                               |             |  |
| *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |  |   |               |                              |                 |   |                               |             |  |